

Search Notes



Application/Control No.

10/675,244

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

MULLER ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
All searches updated		02.23.05	Hn

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	02.23.05	Hn